Search Notes

Application/Control No
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Applicant(s)/Patent under Reexamination

10/088,218

SCHRADER ET AL. Art Unit

Examiner

2611

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SEARCHED				
Class	Subclass	Date	Examiner	
375	-224	1/24/2007	EMF	
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EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only—see search history printout)	1/24/2007	EMF .
PALM INVENTORSHIP	1/24/2007	EMF
PLUS Search	1/25/2007	EMF
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